
This is an electronic reprint of the original article.
This reprint may differ from the original in pagination and typographic detail.

Author(s): Grojo, D. & Delaporte, Ph. & Sentis, M. & Pakarinen, O. H. & Foster, Adam S.

Title: The so-called dry laser cleaning governed by humidity at the nanometer scale

Year: 2008

Version: Final published version

Please cite the original version:

Grojo, D. & Delaporte, Ph. & Sentis, M. & Pakarinen, O. H. & Foster, Adam S. 2008. The so-called dry laser cleaning governed by humidity at the nanometer scale. *Applied Physics Letters*. Volume 92, Issue 3. 033108/1-3. ISSN 0003-6951 (printed). DOI: 10.1063/1.2832766

Rights: © 2008 AIP Publishing. This article may be downloaded for personal use only. Any other use requires prior permission of the author and the American Institute of Physics. The following article appeared in *Applied Physics Letters*, Volume 92, Issue 3 and may be found at <http://scitation.aip.org/content/aip/journal/apl/92/3/10.1063/1.2832766>.

All material supplied via Aaltodoc is protected by copyright and other intellectual property rights, and duplication or sale of all or part of any of the repository collections is not permitted, except that material may be duplicated by you for your research use or educational purposes in electronic or print form. You must obtain permission for any other use. Electronic or print copies may not be offered, whether for sale or otherwise to anyone who is not an authorised user.



The so-called dry laser cleaning governed by humidity at the nanometer scale

D. Grojo, Ph. Delaporte, M. Sentis, O. H. Pakarinen, and A. S. Foster

Citation: [Applied Physics Letters](#) **92**, 033108 (2008); doi: 10.1063/1.2832766

View online: <http://dx.doi.org/10.1063/1.2832766>

View Table of Contents: <http://scitation.aip.org/content/aip/journal/apl/92/3?ver=pdfcov>

Published by the [AIP Publishing](#)

Articles you may be interested in

[Removing imperceptible fluoride residue after chemical dry-cleaning to fabricate uniform low-resistance NiSi film](#)
J. Vac. Sci. Technol. B **29**, 051203 (2011); 10.1116/1.3622301

[Strain partition of Si/SiGe and SiO₂/SiGe on compliant substrates](#)
Appl. Phys. Lett. **82**, 3853 (2003); 10.1063/1.1578168

[Removal versus ablation in KrF dry laser cleaning of polystyrene particles from silicon](#)
J. Appl. Phys. **92**, 5159 (2002); 10.1063/1.1503854

[Dry laser cleaning of particles from solid substrates: Experiments and theory](#)
J. Appl. Phys. **90**, 2135 (2001); 10.1063/1.1389477

[Removal of small particles on silicon wafer by laser-induced airborne plasma shock waves](#)
J. Appl. Phys. **89**, 6496 (2001); 10.1063/1.1353562

An advertisement for the journal AIP Applied Photonics. The background is a vibrant orange and red gradient with a bright sunburst effect on the right. On the left, there is a small image of the journal cover, which features a blue and white abstract design. A yellow starburst graphic with the words 'OPEN ACCESS' is overlaid on the bottom right of the journal cover. To the right of the journal cover, the text 'Launching in 2016!' is written in a large, white, sans-serif font, followed by 'The future of applied photonics research is here' in a smaller, white, sans-serif font. In the bottom right corner, the AIP APL Photonics logo is displayed in white.

The so-called dry laser cleaning governed by humidity at the nanometer scale

D. Grojo,^{a)} Ph. Delaporte,^{b)} and M. Sentis

LP3, UMR 6182, CNRS - Université de la Méditerranée, Case 917, 13288 Marseille Cedex 9, France

O. H. Pakarinen and A. S. Foster

Laboratory of Physics, Helsinki University of Technology, P.O.Box 1100, FI-02015 TKK, Finland

(Received 4 October 2007; accepted 18 December 2007; published online 25 January 2008)

Illumination with single nanosecond pulses leads to the detachment of silica particles with 250 nm radii from silicon surfaces. We identify two laser-energy dependent cleaning regimes by time-of-flight particle-scattering diagnostics. For the higher energies, the ejection of particles is produced by nanoscale ablation due to the laser field enhancement at the particle-surface interface. The damage-free regime at lower energy is shown to be governed by the residual water molecules, which are inevitably trapped on the materials. We discuss the great importance that the humidity plays on the cleaning force and on the adhesion in the experiments. © 2008 American Institute of Physics. [DOI: 10.1063/1.2832766]

Pulsed laser radiation can induce the detachment of nanometer-size particles from various materials surfaces allowing a laser process to be envisioned for advanced cleaning applications related to the fabrication of nanoscale devices.^{1,2} However, although the dry laser cleaning (DLC) approach has been extensively studied for more than 15 years now, there is still a lack of knowledge of its underlying mechanisms. Studies have identified different physical processes which contribute to the cleaning force, but little is known about the importance of each of them. Historically, DLC was explained on the basis of a mechanical ejection resulting from the rapid thermal expansion of the irradiated materials³ and described accurately by recent models.^{4,5} However, Mosbacher *et al.*⁶ reported that damage-free DLC is impossible with short pulses (<6 ns). The local substrate ablation due to the optical near field enhancement underneath the particles is the dominant cleaning mechanism for all their tested situations. In addition, further experimental investigations showed a relatively strong ambient humidity dependence of the particle removal efficiency.^{7,8} They revealed that the cleaning force provided by the laser-evaporated water, which is previously condensed from the ambient onto the surface materials, can be of particular importance.

In this letter, we measure the laser pulse energy dependence of the time of flight (TOF) of the removed particles to identify (by the ejection dynamics) the validity domains of these processes. The irradiated materials are isolated 250 nm radius silica spheres (Kisker-Biotech) supported by silicon (100) substrates. The native oxide layer coverage of the surfaces makes them hydrophilic. We measured a water contact angle of $18 \pm 2^\circ$. The samples are placed in a vacuum chamber with a residual pressure less than 5×10^{-2} Pa to avoid slowing down of the particles in the observed region. The cleaning laser was an ArF ($\lambda_{\text{las}}=193$ nm) excimer laser source (Lambda Physik, LPX220i) delivering pulses of 15 ns

duration. An experimental approach based on forward scattering detection is used to perform the TOF measurements. The experimental configuration is described in detail in Ref. 9. As the ejected particles propagate into a cw probe beam ($\lambda=532$ nm), we perform time- and space-resolved imaging of the particle clouds with the aid of a fast intensified charge coupled device (Princeton Instruments, model 576/RB-E).

Figure 1 shows the images captured for different laser fluences F_{las} and delays t varying from 10 to 120 μs . For $F_{\text{las}}=415$ mJ cm^{-2} , we observe as unique feature the detachment of the particles divided into two distinct components propagating with different velocities [Fig. 1(b)]. Although

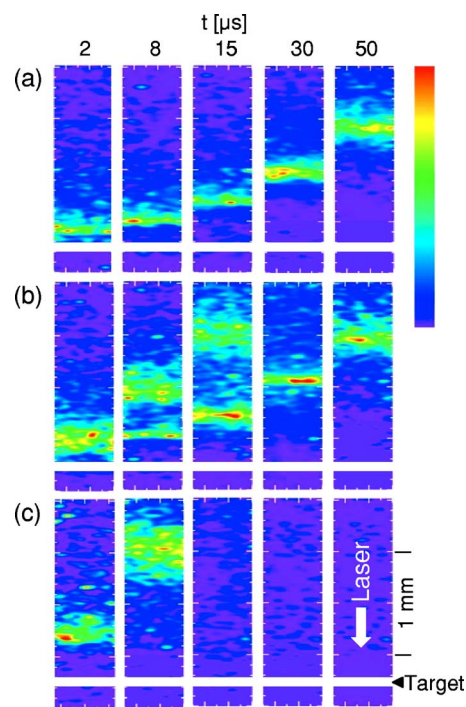


FIG. 1. (Color online) Scattering images of the ejected particles for different laser fluences F_{las} : (a) $F_{\text{las}}=275$ mJ cm^{-2} , (b) $F_{\text{las}}=415$ mJ cm^{-2} , and (c) $F_{\text{las}}=550$ mJ cm^{-2} . The particle cloud propagation is analyzed by capturing images for different delays t between the cleaning laser pulse and the observation gate (1 μs).

^{a)}Electronic mail: david.grojo@nrc-cnrc.gc.ca. Also at National Research Council, Steacie Institute for Molecular Sciences, 100 Sussex Drive, Ottawa, Ontario K1A 0R6, Canada.

^{b)}Electronic mail: delaporte@lp3.univ-mrs.fr

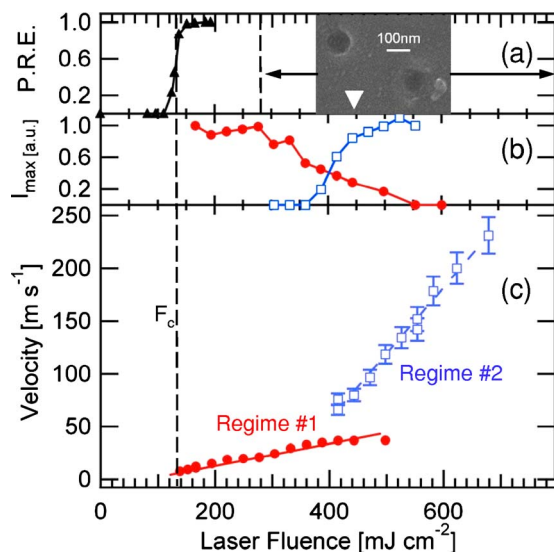


FIG. 2. (Color online) (a) Particle Removal Efficiency (PRE), (b) maximum scattering intensity I_{\max} , and (c) particle velocity corresponding to each ejected cloud as a function of the laser fluence F_{las} . The scattered intensity for the slow (fast) component was measured for a time delay t set to 10 μs (20 μs). The embedded SEM image shows the ablated craters observed for $F_{\text{las}} \approx 430 \text{ mJ cm}^{-2}$.

we study calibrated systems, this observation is in support of the coexistence of two distinct mechanisms leading to the ejection of particles. The only presence of the slow (fast) component for lower (higher) fluences is in agreement with a regime where a single mechanism dominates [Figs. 1(a) and 1(c)].

To analyze these regimes in more detail, Fig. 2 provides the determined detachment velocities of the particles as a function of the laser fluence. Based on optical microscopy analyses, Fig. 2(a) presents the proportion of the particles [particle removal efficiency (PRE)], which are removed by the irradiation as a function of the laser fluence. A sharp threshold value $F_{\text{th}} = F_c \approx 130 \text{ mJ cm}^{-2}$ is found, above which more than 95% of the particles are removed. Above F_c , particles are ejected with a characteristic velocity gradually increasing from 7.6 to 36.8 m s^{-1} [regime 1, Fig. 2(c)]. In the range of 300–500 mJ cm^{-2} , the scattered intensity from the particle cloud decreases while a faster component signal prevails [Fig. 2(b)]. This evidences the transition between two regimes with different mechanisms. In the highest fluence regime (regime 2), the remained particle cloud acquires considerably more speed when increasing laser fluence. The propagation velocity of this scattering component linearly increases from 66 to 231 m s^{-1} when fluence is varied from 415 to 680 mJ cm^{-2} .

We carefully analyzed, by means of scanning electron microscopy (SEM) and atomic force microscopy, the effect of the laser pulse energy on the surfaces. In agreement with the systematic observation of ablated craters [Fig. 2(a)] for F_{las} above 280 mJ cm^{-2} , the fast ejection dynamics regime (2) is governed by a local substrate ablation mechanism. The typical diameter of the ablated craters is $130 \pm 15 \text{ nm}$, which is consistent with the spatial distribution of the near field enhancement calculated by the Mie theory.¹⁰ In this fluence range, the estimated surface temperature reaches values above the evaporation temperature of silicon (2628 K). Then, the particle velocity is gained by momentum transfer from the ablated species.

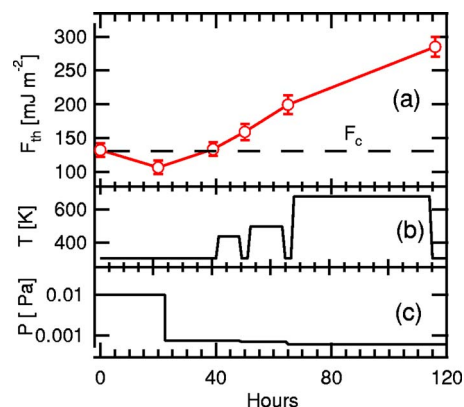


FIG. 3. (Color online) (a) Increase of the particle removal fluence threshold F_{th} over time when water vapor progressively desorbs from surfaces. (b) The sample holder in the vacuum chamber is backside equipped with a halogen lamp to perform successive baking steps under (c) a decreasing atmosphere pressure.

The existence of the regime 1, in which we do not observe damage, shows that the removal by a damage-free process is feasible. However, its identification becomes more complex. First, the measured ejection velocity for laser fluences slightly above F_c is two orders of magnitude higher than the thermally induced expansion velocity of the substrate for similar conditions.^{9,11} Thus, we concluded that the dynamics of materials is not fast enough to explain the detachment of particles in the experiments.

This regime exhibits ejection velocities which remain more likely compatible with another ablative mechanism. It is known that hydrophilic silicon exposed to ambient air with its attendant humidity becomes covered with, at minimum, a monolayer of water molecules. Experimental analyses reveal also spontaneous adsorption of water molecules into small interstices even in ultrahigh vacuum.¹² Thus, it is worthwhile to examine the role that the laser ablation of the trapped humidity can play in these experiments which are performed without delay after the substrates are placed in the vacuum chamber. As shown in Fig. 3, we heated the samples to progressively desorb water from the surfaces. Then, the laser energy threshold measurements [see Fig. 2(a)] are repeated at ambient temperature $T_0 \approx 300 \text{ K}$ between each baking step [Fig. 3(b)] to evaluate the role of the evaporated water molecules. Figure 3 shows that the reduction of humidity over time is accompanied by an apparent increase in the laser energy required to eject the particles. For the studied situation, the removal threshold fluence changes by a factor ≈ 2.1 [Fig. 3(a)] and reaches a value which is similar to the substrate damage threshold, i.e., where only the first identified ejection mechanism plays a role. This is clear evidence that the presence of water in the studied systems is required for the existence of the ejection mechanism responsible for the regime 1.

The adhesion of dry submicrometer objects to surfaces is mainly provided by the van der Waals forces. A typical value of this adhesion force for submicron particles is $\approx 100 \text{ nN}$.¹³ Nevertheless, numerous authors report the formation of a water meniscus at the nanoparticle-surface interstices for moderated relative humidity (RH) atmospheres.^{14,15} In this case, the subsequent contribution of the capillary force to the adhesion is usually estimated by the standard approximation $F_c = 4\pi\gamma R$, where γ is the surface tension of water (7.28

$\times 10^{-4} \text{ N cm}^{-1}$). For particles as small as $R=250 \text{ nm}$, this force ($\approx 220 \text{ nN}$) is not negligible and can clearly dominate the interaction. However, since the saturated vapor pressure of water is 2340 Pa , our pressure atmosphere of 10^{-2} Pa (in the initial stage) means $\text{RH} \approx 10^{-3}\%$. For this humidity, the Kelvin equation gives a curvature radius of 0.5 \AA for the condensed liquid meniscus. Thus, our system is clearly out of the validity domain of these continuum models and a real liquid meniscus cannot be envisioned. However, the Fig. 3 shows that the removal threshold F_{th} exhibits a nonmonotonous evolution when water progressively desorbs. In a first stage ($< 20 \text{ h}$), we measured a fluence threshold reduction to $\approx 0.8 \times F_c$ as well as a significant increase of the particle kinetic energy $\Delta E_k/E_k \approx 2.7$. According to Ref. 12, this may indicate the elimination of some residual water molecules which were still trapped into the contact line of the particles and which contributed to the adhesion (at t_0). Indeed, the desorption rate of these molecules during pump down is initially faster than that of those forming the surface monolayer coverage since water-to-water bonds are weaker than water-to-solid ones.¹⁶ Then, particle-surface adhesion and the subsequent removal threshold decreases before than the monolayer is affected. The laser threshold measurements show that the contribution of these trapped molecules to the total particle-surface adhesion is about 20% (initially). This is a relatively strong effect for a very low water volume such as expected. In fact, assuming the 250 nm spheres are compressed according to the Johnson-Kendall-Roberts theory predictions (10 nm radius contact area) and a maximum of approximately four water molecules layer are trapped into the particle contact lines, we still have more than 100 times more molecules in the monolayer underneath the particle (10–250 nm from the center) than in the molecular meniscus. From these estimations combined with our observations, we can conclude that a molecular-size meniscus can still exist under vacuum. However, the ejection of particles results mainly from the laser ablation of the water monolayer coverage rather than that of the meniscus as it was established for studies at higher RH where real liquid meniscus are formed.^{7,8}

In conclusion, our results emphasize that the presence of molecular residual water offers possibility to achieve damage-free laser nanocleaning in a limited energy-operating

window (regime 1). This is of practical importance for applications like microelectronics, where strictly nonconsuming substrate cleaning methods are needed. We highlight that the humidity governs most of physical processes naturally involved in the experiments. However, since in vacuum the water molecules do not form real menisci below particles, continuum models fail. For real quantitative analysis of the role of water in the studied systems, we emphasize that molecular studies would be needed. Operation in regime 2 defines a region to produce patterning of solid surfaces with near-field resolutions. Studies on this aspect^{10,17,18} should lead to the development of photonic-based colloidal lithography techniques for creating various functional nanostructured materials.

¹W. Zapka, W. Ziemlich, and A. C. Tam, *Appl. Phys. Lett.* **58**, 2217 (1991).

²O. Yavas, N. Suzuki, M. Takai, A. Hosono, and S. Kawabuchi, *Appl. Phys. Lett.* **72**, 2797 (1998).

³A. C. Tam, W. P. Leung, W. Zapka, and W. Ziemlich, *J. Appl. Phys.* **71**, 3515 (1992).

⁴N. Arnold, *Appl. Surf. Sci.* **208**, 15 (2003).

⁵B. S. Luk'yanchuk, Z. B. Wang, W. D. Song, and M. H. Hong, *Appl. Phys. A: Mater. Sci. Process.* **79**, 747 (2004).

⁶M. Mosbacher, H. J. Munzer, J. Zimmermann, J. Solis, J. Boneberg, and P. Leiderer, *Appl. Phys. A: Mater. Sci. Process.* **72**, 41 (2001).

⁷G. Vereecke, E. Rohr, and M. M. Heyns, *J. Appl. Phys.* **85**, 3837 (1999).

⁸M. Mosbacher, M. Bertsch, H. J. Munzer, V. Dobler, B. U. Runge, D. Bauerle, J. Boneberg, and P. Leiderer, *Proc. SPIE* **4426**, 308 (2002).

⁹D. Grojo, A. Cros, P. Delaporte, and M. Sentis, *Appl. Phys. B: Lasers Opt.* **84**, 517 (2006).

¹⁰A. Pereira, D. Grojo, M. Chaker, P. Delaporte, D. Guay, and M. Sentis (unpublished).

¹¹V. Dobler, R. Oltra, J. P. Boquillon, M. Mosbacher, J. Boneberg, and P. Leiderer, *Appl. Phys. A: Mater. Sci. Process.* **69**, S335 (1999).

¹²R. A. Nevshupa, M. Scherge, and S. I. U. Ahmed, *Surf. Sci.* **517**, 17 (2002).

¹³F. W. Delrio, M. P. De Boer, J. A. Knapp, E. D. Reedy, P. J. Clews, and M. L. Dunn, *Nat. Mater.* **4**, 629 (2005).

¹⁴M. Schenk, M. Futing, and R. Reichelt, *J. Appl. Phys.* **84**, 4880 (1998).

¹⁵O. H. Pakarinen, A. S. Foster, M. Paajanen, T. Kalinainen, J. Katainen, I. Makkonen, J. Lahtinen, and R. M. Nieminen, *Modell. Simul. Mater. Sci. Eng.* **13**, 1175 (2005).

¹⁶P. Danielson, *R&D Mag.* **43**, 57 (2001).

¹⁷W. J. Cai and R. Piestun, *Appl. Phys. Lett.* **88**, 111112 (2006).

¹⁸Y. Zhou, M. H. Hong, J. Y. H. Fuh, L. Lu, B. S. Luk'yanchuk, Z. B. Wang, L. P. Shi, and T. C. Chong, *Appl. Phys. Lett.* **88**, 023110 (2006).